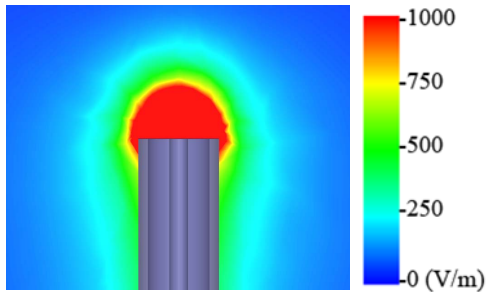


## Model-Based Dielectric Measurement Techniques Using Custom Open-Ended Coaxial Probes

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**Figure 1a: Probe HFSS Model**



**Figure 1b. Probe and Portable VNA**

A model-based dielectric measurement technique using custom open-ended coaxial probes has been developed for *in situ* measurements of vegetation, as well as for *in vivo* measurement of biological tissue dielectric constant. The impracticality of repeated device calibration, especially in time-limited field campaigns or in the operating room in the case of biological tissue, along with the high cost of commercial probes, has motivated the development of this model-based technique for accurate characterization of dielectric constant without the need for traditional three-standard probe calibration methods. Instead, this dielectric characterization technique relies on the use of precise finite element modeling of a specific probe geometry in order to generate a pre-computed lookup table linking the S-parameter measurement (using a VNA) to the corresponding complex dielectric constant for the material under test (spanning the expected range in the table below).

$\epsilon_r$ : 1 – 80	$\sigma$ : 0 – 10 (S/m)	$f$ : 0.3 – 6 GHz
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A set of custom dielectric probes were fabricated with identical geometry by machining semi-rigid coaxial cables (0.086” OD) to a uniform length. Each probe was experimentally characterized by measuring the complex  $S_{11}$  parameter with the open end in air. A full-wave model of this cable geometry was then created in Ansoft HFSS (Figure 1a), and the model parameters were determined by iterative refinement to achieve the best fit for the  $S_{11}$  measurement in air across the frequencies of interest. Using this model, the lookup table of complex  $S_{11}$  data was then generated for the values of permittivity ( $\epsilon_r$ ), conductivity ( $\sigma$ ), and frequency shown in the table above.

The presentation will discuss practical issues with *in situ* dielectric measurements using a portable VNA (Figure 1b). Furthermore, permittivity measurements obtained using the model-based technique as well as commercial software will be presented to illuminate practical advantages of probe modeling. The  $S_{11}$ - $\epsilon_r$  lookup method will be outlined with emphasis on open-ended air  $S_{11}$  measurements used to correct any probe and cable induced errors and calibration drifts.